# **PH7030AL**

# N-channel TrenchMOS logic level FET

Rev. 03 — 12 January 2010

**Product data sheet** 

# 1. Product profile

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing and consumer applications.

#### 1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

### 1.3 Applications

- Consumer applications
- Desktop Voltage Regulator Module (VRM)
- Notebook Voltage Regulator Module (VRM)

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	30	V
$I_D$	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u>	-	-	76	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	51	W
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$	-	2.9	-	nC
$Q_{G(tot)}$	total gate charge	V <sub>DS</sub> = 12 V; see <u>Figure 14</u> and <u>15</u>	-	10	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}$	-	4.9	7	mΩ



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb (	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH7030AL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$	-	30	V
$V_{DGR}$	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
$V_{GS}$	gate-source voltage		-20	20	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{M}}$	-	53	Α
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	-	76	Α
I <sub>DM</sub>	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3	-	260	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	51	W
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dra	ain diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	65	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	260	Α
Avalanche	ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 65 A; $V_{sup}$ ≤ 30 V; $R_{GS}$ = 50 Ω; unclamped	-	21	mJ

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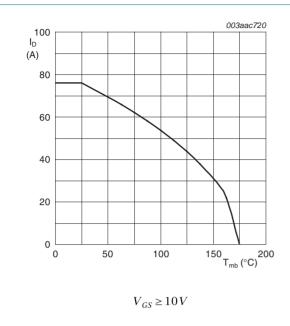


Fig 1. Continuous drain current as a function of mounting base temperature

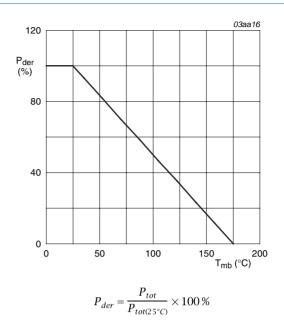
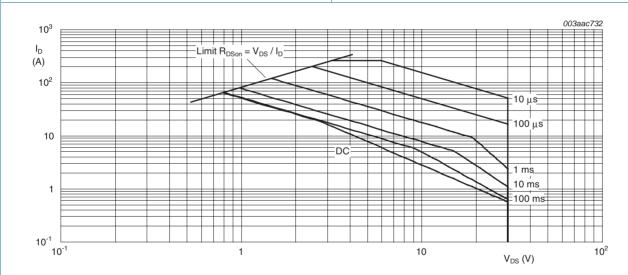


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$  is single pulse

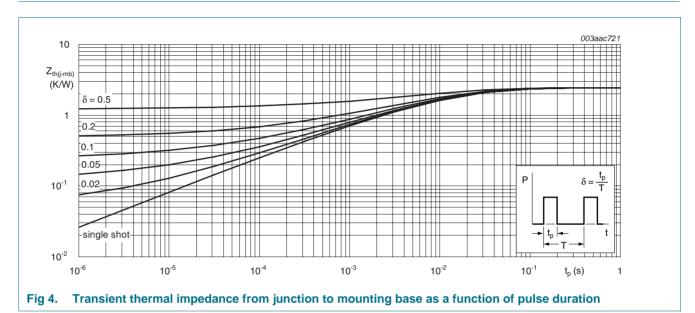
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

### N-channel TrenchMOS logic level FET

### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	1.4	2.45	K/W



### N-channel TrenchMOS logic level FET

### 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 20 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; t_{av} = 100 \text{ ns}$	35	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
		$I_D$ = 250 $\mu$ A; $V_{GS}$ = 0 V; $T_j$ = -55 °C	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 11</u> and <u>12</u>	1.3	1.7	2.15	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 150 °C; see <u>Figure 12</u>	0.65	-	-	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; see <u>Figure 12</u>	-	-	2.45	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		$V_{GS}$ = -16 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	6.97	9.1	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 ^{\circ}\text{C};$ see Figure 13	-	-	12.2	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	4.9	7	mΩ
$R_G$	gate resistance	f = 1 MHz	-	0.6	1.5	Ω
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14 and 15	-	10	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	20	-	nC
		$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 10 \text{ V}$ ; see Figure 14 and 15	-	22	-	nC
$Q_{GS}$	gate-source charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	3.7	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge	see <u>Figure 14</u> and <u>15</u>	-	2.1	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	1.6	-	nC
Q <sub>GD</sub>	gate-drain charge		-	2.9	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = 12 \text{ V}$ ; see Figure 14 and 15	-	2.6	-	V
C <sub>iss</sub>	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}; T_j = 25 \text{ °C};$	-	1270	-	pF
C <sub>oss</sub>	output capacitance	see Figure 16	-	255	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	145	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	24	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \Omega$		39	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	30	-	ns
t <sub>f</sub>	fall time		_	11	-	ns

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Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 17</u>	-	0.88	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	30	-	ns
Qr	recovered charge	$V_{DS} = 20 \text{ V}$	-	22	-	nC

[1] Tested to JEDEC standards where applicable.

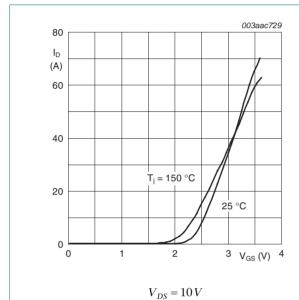
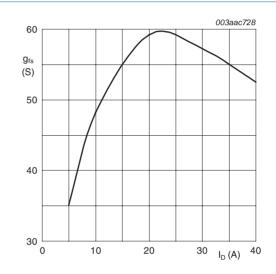


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$T_j = 25 \,^{\circ}C; V_{DS} = 15 \, V$$

Fig 6. Forward transconductance as a function of drain current; typical values

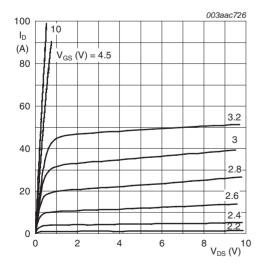
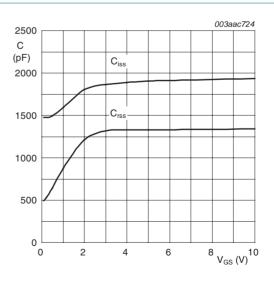


Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values

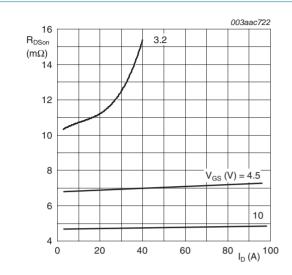
 $T_j = 25 \,{}^{\circ}C; t_p = 300 \,\mu s$ 



 $V_{DS} = 0V; f = 1MHz$ 

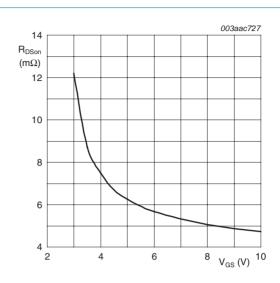
Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

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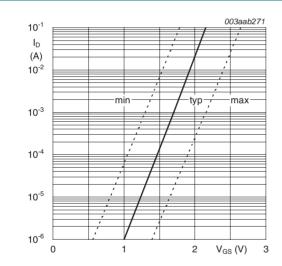
 $T_j = 25 \,{}^{\circ}C; t_p = 300 \,\mu s$ 

Fig 9. Drain-source on-state resistance as a function of drain current; typical values



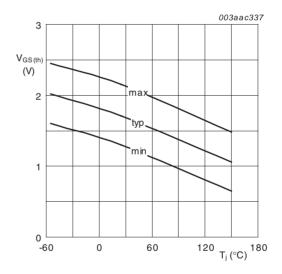
$$T_j = 25 \,^{\circ}C; I_D = 15A$$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $T_i = 25 \,^{\circ}C; V_{DS} = 5 \, V$ 

Fig 11. Sub-threshold drain current as a function of gate-source voltage



$$I_D = 1 \, mA; V_{DS} = V_{GS}$$

Fig 12. Gate-source threshold voltage as a function of junction temperature

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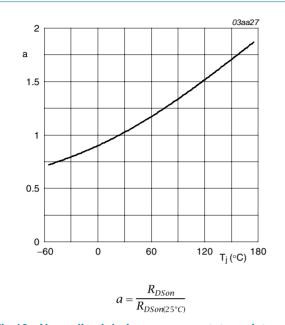


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

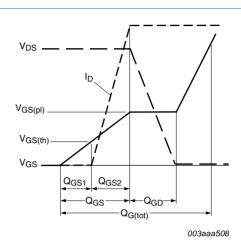


Fig 14. Gate charge waveform definitions

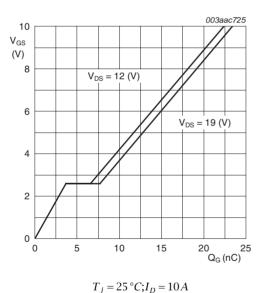
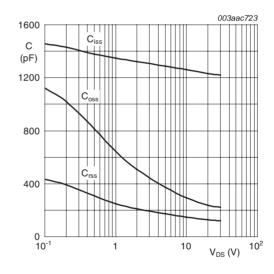


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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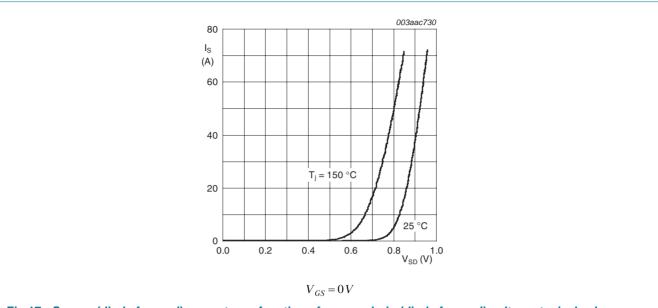
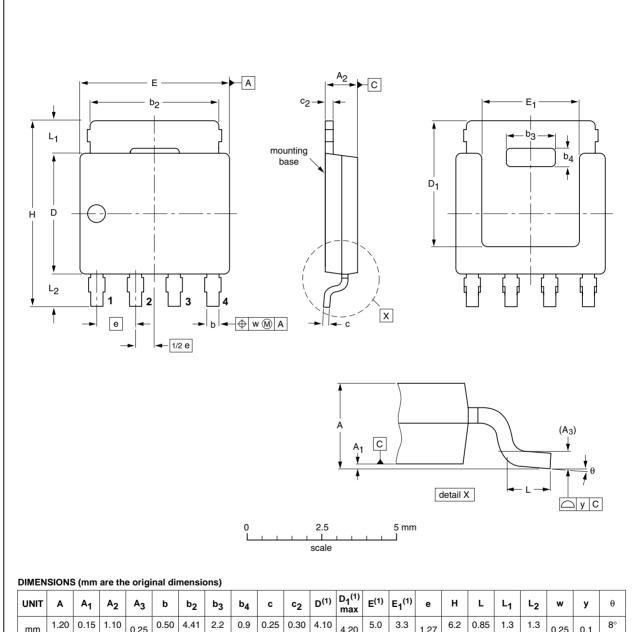


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

### Package outline

### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



	UNIT	Α	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b	b <sub>2</sub>	b <sub>3</sub>	b <sub>4</sub>	С	c <sub>2</sub>	D <sup>(1)</sup>	D <sub>1</sub> <sup>(1)</sup> max	E <sup>(1)</sup>	E <sub>1</sub> <sup>(1)</sup>	е	Н	L	L <sub>1</sub>	L <sub>2</sub>	w	у	θ
	mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	l .	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°
L		1.01	0.00	0.33		0.00	3.02	2.0	0.7	0.13	0.24	5.00		4.0	0.1		3.0	0.40	0.0	0.0			U

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

	OUTLINE		REFER	EUROPEAN	ISSUE DATE		
	VERSION	IEC	JEDEC	JEITA	PROJECTION	1330E DATE	
	SOT669		MO-235			<del>04-10-13</del> 06-03-16	
_							

Fig 18. Package outline SOT669 (LFPAK)

### N-channel TrenchMOS logic level FET

# 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH7030AL_3	20100112	Product data sheet	-	PH7030AL_2
Modifications:	<ul> <li>Various cha</li> </ul>	anges to content.		
PH7030AL_2	20090121	Product data sheet	-	PH7030AL_1
PH7030AL_1	20080819	Preliminary data sheet	-	-

#### N-channel TrenchMOS logic level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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